


<b>Search Notes</b> 	<b>Application/Control No.</b> 10572798	<b>Applicant(s)/Patent Under Reexamination</b> ADACHI ET AL.
	<b>Examiner</b> Chau N Nguyen	<b>Art Unit</b> 2831

SEARCHED			
Class	Subclass	Date	Examiner
174	73.1	1/31/08	CN
174	74R	7/30/08	CN
update	all	7/31/08	CN

SEARCH NOTES		
Search Notes	Date	Examiner
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INTERFERENCE SEARCH			
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